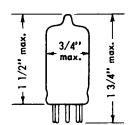
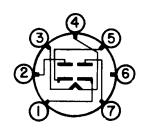
TECHNICAL INFORMATION

RELIABLE DOUBLE DIODE

TYPE CK5726/ 6AL5W/ 6097





BOTTOM VIEW

6B T

once in Elettronics

The CK5726/6AL5W/6097 is a heater-cathode type double-diode of miniature construction designed for dependable operation under conditions usually found in mobile and aircraft applications. The heaters are designed to minimize the possibility of failure under severe intermittent on-off operation. The heaters for the two diode units are internally connected in series so that a heater failure makes both units inoperative.

MECHANICAL DATA

ENVELOPE: T-5½ Glass

BASE: Miniature Button 7-Pin

TERMINAL CONNECTIONS:

Pin 1 Cathode, Unit #1
Pin 2 Plate, Unit #2
Pin 3 Heater
Pin 4 Heater

Pin 5 Cathode, Unit #2
Pin 6 Internal Shield
Pin 7 Plate, Unit #1

MECHANICAL RATINGS:

Maximum Impact Acceleration (Shock Test - Note 3)

Maximum Vibrational Acceleration (96 Hour Fatigue Test - Note 4)

Maximum Bulb Temperature

720 G

2.5 G

165 °C

MOUNTING POSITION: Any

ELECTRICAL DATA

Caution ----- To Electron Equipment Design Engineers. Special attention should be given to the temperature at which the tubes are to be operated. Reliability will be seriously impaired if maximum bulb temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the tube and will be reduced appreciably if absolute maximum ratings are exceeded. Both reliability and performance will be jeopardized if filament voltage ratings are exceeded. Life and reliability of performance are directly related to the degree that regulation of the heater voltage is maintained at its center rated value.

			NORMAL			
RATINGS AND NORMAL OPERATION:	MIL-E-1B SYMBOL	ABSOLUTE MINIMUM	TEST CONDITIONS (Note 6)	NORMAL OPERATION (Note 5)	ABSOLUTE MAXIMUM	MIL-E-1B UNITS
Heater Voltage (Note 7)	Ef:	5 .7	6. 3	6.3	6.9	٧
Plate Supply Voltage (RMS)(each plate):	Epp:	••••	165	117	••••	Vac
Load Resistance	RL:		11,000			ohms
Filter Input Capacitance	CL:		8	8	••••	μ f
Peak Inverse Plate Voltage	epx:			• • • •	360	'n
Steady State Peak Plate Current (each plate)	ib/p:	••••	••	•	60	mA
DC Output Current (each plate)	lo/p:	••••	••••	9	10	mAdc
Peak Transient Plate Current (each plate)	i surge/p:	••••	••••	••••	350	mA
Heater - Cathode Voltage	Ehk:				360	٧
Minimum Effective Plate Supply Impedance (per Plate)	Z _p /p:	••••	••••	300	••••	ohms

CHARACTERISTICS AND QUALITY CONTROL TESTS (Note 1) (In the following tests, each unit is tested separately)

TEST	CONDITIONS	AQL %	MIL - E - 1B SYMBOL	MIN.	BOGIE	MAX.	MIL-E-1B UNITS
ACCEPTANCE TES	TS - GROUP C						
Continuity and Short		0.4					
ACCEPTANCE TES	TS - GROUP D. COMBINED	AQL=1.0%					
Heater - Current :		0.65	lf:	275	300	325	mA
	-						

Tentative Data

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RELIABLE DOUBLE DIODE

ELECTRICAL DATA (cont'd)

CHARACTERISTICS AND QUALITY CONTROL TESTS (Note 1)(cont'd)

TEST	CONDITIONS		AQL MIL-E-1B % SYMBOL		MIN.	. BOGIE M		MAX. MIL-E-1B UNITS	
ACCEPTANCE TESTS	GROUP D (cont'd)								
Heater - Cathode Leakage: Operation: Emission (1):	Ehk=100 Vdc: Heater Positive Ehk=100 Vdc: Heater Negative Full Wave Operation		0.65 lhk: 1hk: 0.65 lo: 0.65 ls:		16 40	18	10 10	μAdc μAdc mAdc mAdc	
ACCEPTANCE TESTS	S - GROUP E								
Insulation of Electrodes: Emission (2): Plate Current: Plate Current Differ - ence between diodes:	Ef= 6.3 V; Ep-all= -300 Vdc Esd-all= -300 Vdc Eb= 7.0 Vac: (Note 8) Ebb= 0; Rp= 40,000 ohms Ebb= 0; Rp= 40,000 ohms	2 2 2	Δ Is (2): Δ Is:		100		15 20 5	Meg. Meg. % μAdc μAdc	
Hum:	Ef= 7.0 Vac	2.	5 Eo:				10	m∨ac	
ACCEPTANCE TESTS	S - GROUP F							_	
Capacitance: (Note 2) Low Pressure Voltage	Plate #1 to Plate #2 Plate to (htktint.sd.text.sd Cathode to (htptint.sd.text.		C:		2.4 3.1 500		0.026 4.0 4.7	іці іці Уас	
Breakdown: ACCEPTANCE TESTS	C CDOUR A								
	S - GROUP A Hammer Angle = 48°; Epp/p=	. 0							
Shock:	⊓ammerAng≀e−4ο ;⊏pp/p− (Note 3)						••••	••••	
Fatigue: Post Shock and Fatigue Test End Points: Heater-Cathode	96 Hours: (Note 4) Ehk=+100 Vdc	6.	5 Ihk:				15	μAdc	
Leakage:	Ehk= - 100 Vdc		ļhk:				15	μAdc	
Operation:	Full-Wave Circuit		lo:		14			mAdc	
ACCEPTANCE TESTS	S - GROUP B								
Glass Strain:		2.	5 -			• • • •	••••	••••	
TESTS	CONDITIONS	AQL %	MIL-E-1B SYMBOL	MIN.	MAX.	MIL - E UNIT	rs	Maximum defects per Characteristics 1 st Combined ample Sample	
ACCEPTANCE LIFE	TEST								
Heater Cycling:	Ef= 7.5 V; Ehk=+135 Vdc; Epp= 0; 1 min. on, 1 min. of			2000	••••	Cycle	s		
Heater Cycling Life Test End Points: Heater - Cathode Leakage: 1 Hour Stability Life Test: 1 Hour Stability Life	Heater Positive Heater Negative TA=Room; Ehk=Eo+ 117 Vac; Full wave circuit		lhk: lhk:		20 20	μAdc μAdc			
from initial: 100 Hour Survival Rate Life Test:	Eb=7.0 Vac (Typical sample size=50 tubes) TA=Room; Ehk=Eo+ 117 Vac; full wave circuit	1.0	Δ , Is (2):		10	%			
100 Hour Survival Rate Life Test End Points: Inoperatives:		0.65		••					
500 and 1000 Hour In- termittent High Tem- perature Life Test:	T Bulb=165°C; Ehk= Eo+117Vac; Full wave circuit.		•		••••				

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RELIABLE DOUBLE DIODE

ELECTRICAL DATA (cont'd)

TESTS	CONDITIONS	AQL %	MIL - E - 1B Symbol	MIN.	MAX.	MIL-E-1B UNITS	Maximum defects per Characteristics 1 st Combined Sample Samples	
ACCEPTANCE LIFE	TEST (cont'd)						•	·
500 Hour Intermittent His Temperature Life End Points: Inoperatives: Heater Current: Heater - Cathode Leak Emission (1):	40 tubes 2 nd sample (Total allowable con 1 st sample 8 tubes 1) abined defects= st and 2 nd san	=4 tubes nple) If: Ihk: Is(1):	275	325 10	mA μAdc mAdc	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	3 3 3 5
Plate Current: Electrode Insulation:	(p-all) (sd-all)		lb: Rp-all: Rsd-all:	2 50 50	20	μAdc Meg. Meg.	2	5
Emission (2): 1000 Hour Intermittent High Temperature	(Typical sample size 1 st sample 40 tubes		ls (2):	••••	15	%	2	5
Life Test End Points: Inoperatives: Heater Current: Heater - Cathode Leak Emission (1):			lf: lhk: ls (1):	275	325 10	mA μAdc mAdc	2 2 2 2	5 5 5 5

NOTES

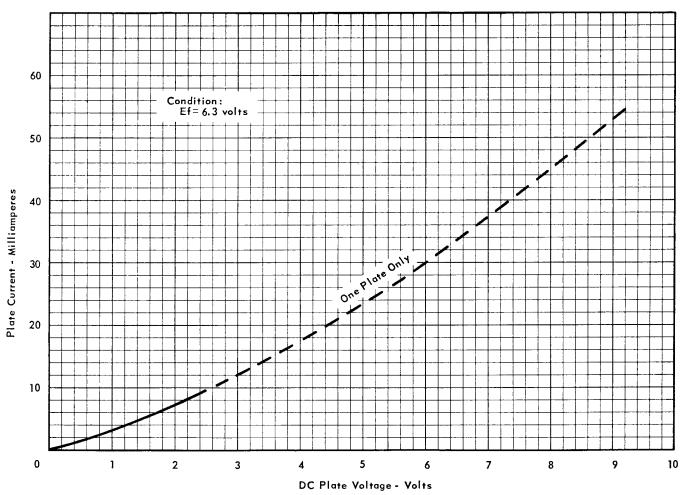
- Note 1: Characteristics, Quality Control Test Procedures, and Inspection Levels are made according to the appropriate paragraphs of MIL-E-1B, "Inspection Instructions for Electron Tubes," and MIL-STD-105A.
- Note 2: With Shield #316.
- Note 3: Test Conditions and Acceptance Criteria per Shock Test Procedures of Mil-E-1B basic specifications.
- Note 4: Test Conditions and Acceptance Criteria per Fatigue Test Procedures of MIL-E-1B basic specifications.
- Note 5: These normal values represent conditions at which control of reliability may be excected.
- Note 6: These normal test conditions are used for all characteristic tests unless otherwise stated under the individual test item.
- Note 7: For most applications the performance will not adversily affected by $\pm 10\%$ heater voltage variation, but when the application can provide a closer control of heater voltage an improvement in reliability will be realized.
- Note 8: Change of emission (2) for individual tubes from that value measured at Ef= 6.3 V to that value measured at Ef= 5.7 V.

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RELIABLE DOUBLE DIODE

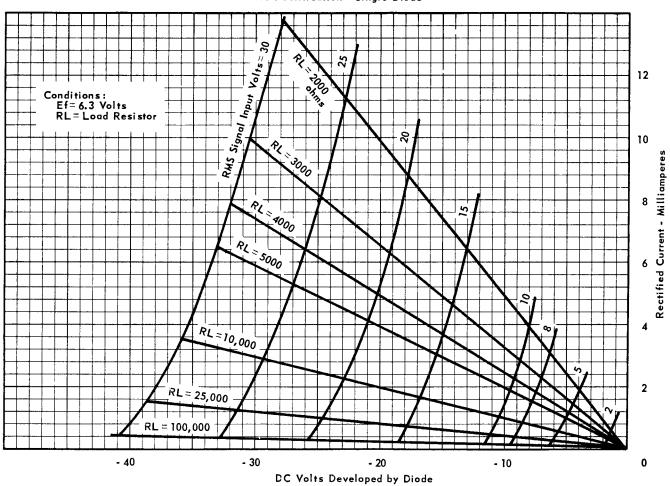
AVERAGE PLATE CHARACTERISTICS



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RELIABLE DOUBLE DIODE

AVERAGE CHARACTERISTICS Half-Wave Rectification - Single Diode



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